

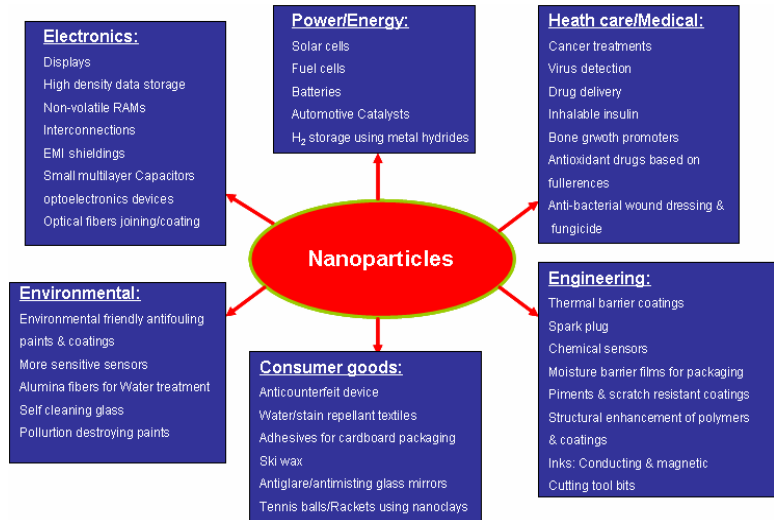
Development of Nano Lead Free Solders –Challenges and Future Research Topics

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Definition of Nano Particles

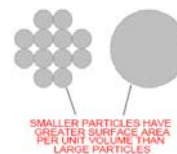
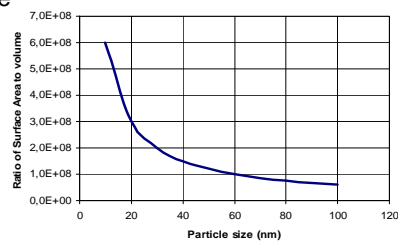
Particles in size range 10^{-9} m are known as nanoparticles or sub-micron particles. They are also known as quantum dots due to quantum property possess by them.

Nanoparticles in Various Fields



Motivation for Development of Nano Lead Free Solders

- **Unique properties of materials in nano-scale**
 - Large surface area per unit volume
 - Large surface energy
 - Low melting point (difference can be as large as 100°C)
- **Depression in melting temperature**
 - Reduce processing temperature
 - Reduce thermal stresses during processing
- **Increased strength of solder alloys**
 - Finer microstructure
 - Less prone to grain coarsening
 - Restriction of dislocation movement and grain boundary sliding
- **Interconnection miniaturization**
 - Very small pitch applications
 - Increase fine pitch interconnection reliability



Approach in Nano Lead Free Soldering

- Nano-size effect: Lower melting point leads to lower reflow temperature
- Grain size control: Bimodal distributed solder system (nano-sized powder mixed together with micro-sized particle technology in solder may improve mechanical properties of the solder joint)

Current Related Research Worldwide on Nano Lead Free Solders

- **iNEMI Lead-Free Nano-Solder Project, USA**
 - Application of Nanotechnology to Suppress Non-Lead Solder Reflow Temperature (Aerodynamics, USA)
- Synthesis and Application of Novel Lead-Free Solders Derived from Sn-based Nanopowders by L. Y. Hsiao, J. G. Duh, “Synthesis and Characterization of the Lead-Free Solders with Sn-3.5Ag-xCu Alloy Nanoparticles by Chemical Reduction Method,” *Journal of The Electrochemical Society*, Vol.152, No.9 (2005), pp.J105-J109.

Experimental Approach

•Elements:

- Cu_6Sn_5 nanopowder, Sn-3.5Ag solder paste (Mechanically Mixing, Ratio: 1.295wt%, Surface finish: ENIG)

•Nanopowders synthesis method:

- Cu_6Sn_5 nanopowders were synthesized by precipitation with sodium borohydride (NaBH_4) in aqueous solutions at room temperature.
- Appropriate amounts of SnSO_4 , AgNO_3 , and $\text{Cu}(\text{NO}_3)_2 \cdot 2.5\text{H}_2\text{O}$ were dissolved in aqueous solutions as the precursors for Cu_6Sn_5 nanopowders.

•Intermetallic Compounds (IMCs)

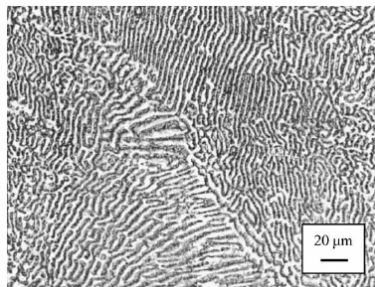
- Needle-type $(\text{Ni,Cu})_3\text{Sn}_4$ and Hexagonal $(\text{Cu,Ni})_6\text{Sn}_5$

•Shear Test Result

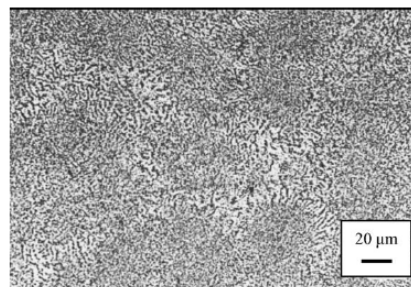
- The ball shear strength of Cu_6Sn_5 -contained joint was shigher than that of the bare SnAgCu one owing to the nano Cu_6Sn_5 reinforcement. However, after more than five reflows, the effect is lost and brittle failure mode controls the ball shear strength.

Effect of nanoparticles to control the grain size

“Influence of titanium dioxide nanopowder addition on microstructural development and hardness of tin–lead solder”, D.C. Lina, G.X. Wang, T.S. Srivatsana, Meslet Al-Hajria, M. Petrarolib, Materials Letters 57 (2003) 3193– 3198.



Conventional eutectic Sn-37Pb



Sn-37Pb with 0.5Wt% titanium dioxide nano-powder

Effect of nanoparticles to control the IMC layer thickness (ECTC 2006)

A Study of Nano Particles in SnAg-Based Lead Free Solders for Intermetallic Compounds and Drop Test Performance

Masazumi Amagai, Modeling and Characterization,
Yasukuba Technology Center, Texas Instruments, Japan

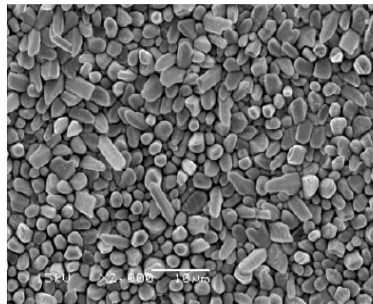
Experimental Approach

Elements: Co, Ni, Pt, Al, P, Cu, Zn, Ge, Ag, In, Sb, Au nano particles Sn-3.0Ag (Multiple reflow 245⁰C, Pull), Sn-1.0Ag solder paste (Drop)

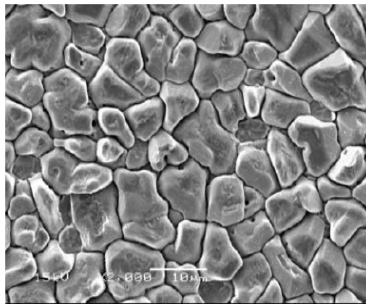
Multiple reflow result: Co, Ni and Pt were solved in IMC, which does not increase IMC grain size and thickness significantly after 4 time solder reflow processes.

Pull test result: Co, Ni or Pt including in Sn-3.0Ag-based lead free solders show low frequency of occurrence of IMC fracture.

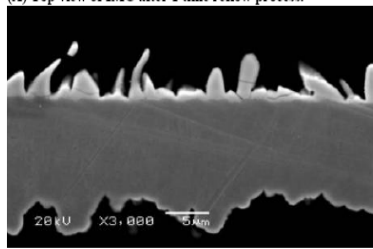
Drop test result: Ni, Co and Pt were very effective to increase the drop test performance.



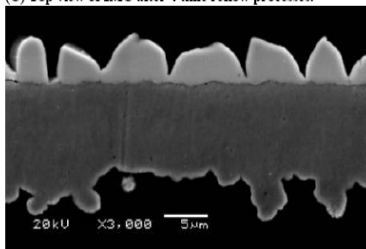
(A) Top view of IMC after 1 time reflow process.



(C) Top view of IMC after 4 time reflow processes.

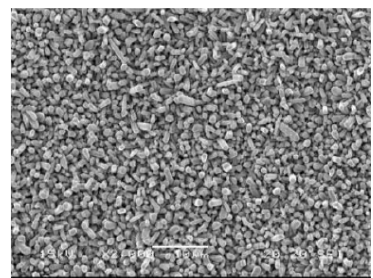


(B) Cross section of IMC after 1 time reflow process.

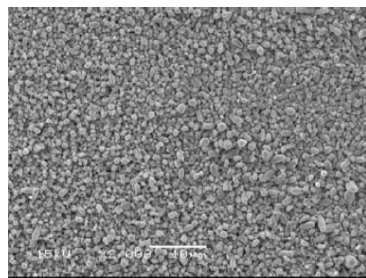


(D) Cross section of IMC after 4 time reflow processes.

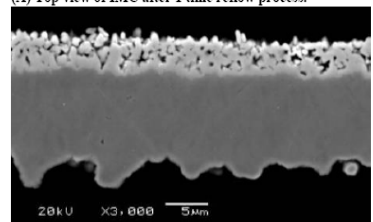
Intermetallic Compounds with Sn-3.0Ag



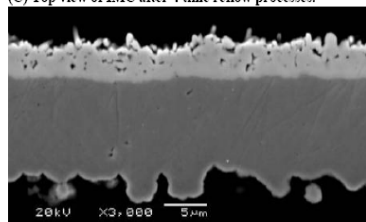
(A) Top view of IMC after 1 time reflow process.



(C) Top view of IMC after 4 time reflow processes.

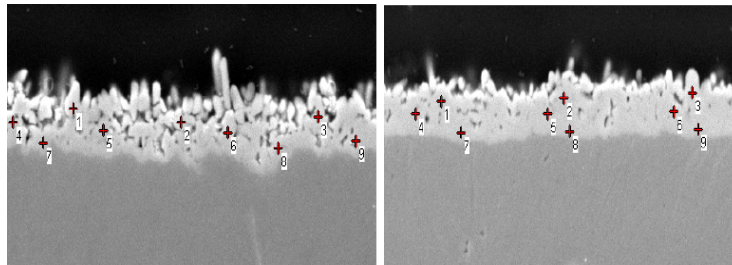


(B) Cross section of IMC after 1 time reflow process.



(D) Cross section of IMC after 4 time reflow processes.

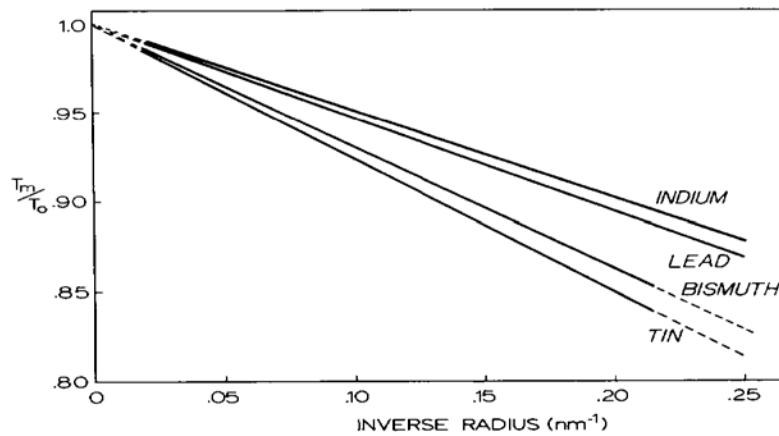
Intermetallic Compounds with Sn-3.0Ag-0.03Co

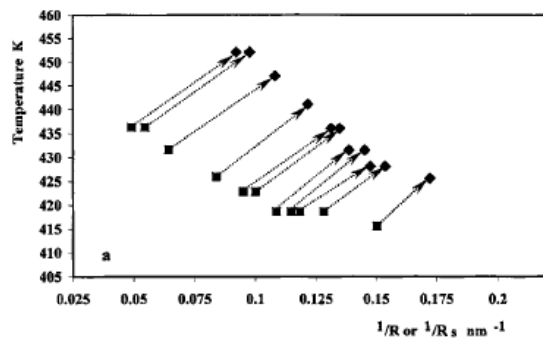


Location	Co	Cu	Sn	Total	Location	Co	Cu	Sn	Total
1 (111,137) -----		45.08	54.92	100.00	1 (101,130) 2.11	42.75	55.14	100.00	
2 (254,150) 3.29		44.21	52.50	100.00	2 (268,127) 1.99	44.53	53.48	100.00	
3 (436,145) 1.87		43.74	54.39	100.00	3 (443,122) 2.38	43.58	54.03	100.00	
4 (31,150) 2.14		44.93	52.92	100.00	4 (66,142) 2.65	45.01	52.34	100.00	
5 (151,158) 2.53		45.20	52.28	100.00	5 (246,142) 1.42	45.88	52.71	100.00	
6 (316,160) 2.43		46.91	50.67	100.00	6 (418,140) 2.02	44.82	53.16	100.00	
7 (71,170) 2.08		48.22	49.71	100.00	7 (128,160) 0.88	48.13	50.99	100.00	
8 (383,175) 2.06		48.21	49.74	100.00	8 (276,159) 0.50	47.99	51.51	100.00	
9 (486,168) 1.77		45.51	52.71	100.00	9 (451,157) 1.66	45.36	52.99	100.00	

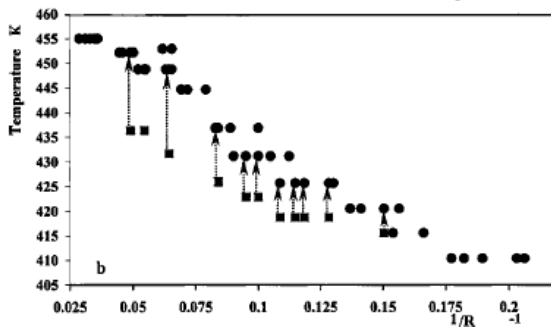
(A) IMC element analysis after 1 time reflow process. (B) IMC element analysis after 4 time reflow processes.

Reduced temperature as reciprocal particle size of In, Pb, Bi and Sn (Allen et al, *Thin Solid Films*, 144 (1986) 297-308)





Solid-liquid equilibria in nanoparticles of Pb-Bi alloys by W. A. Jesser, R. Z. Shneck and W. W. Gile



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Nanoparticles production

Top down Approach

- Mechanical Milling
- Lithography (hybrid technology)
- Electro-explosion (thermal / chemical)
- Laser Ablation (Thermal)
- Spark Erosion (Electric Arc Discharge)

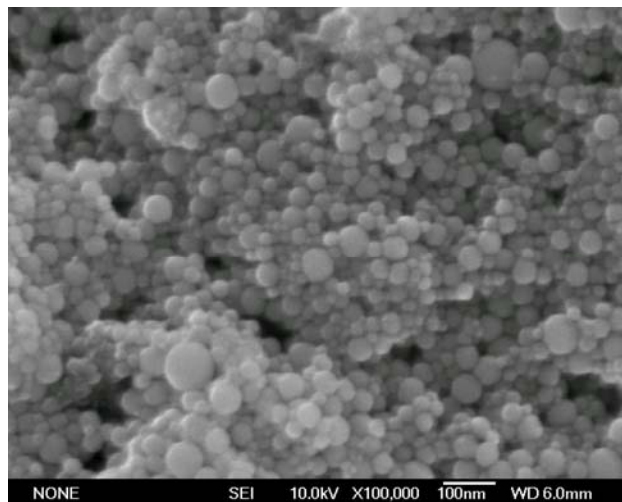
Bottom up Approach

- Sol-gel technique
- Aerosol based process
- Chemical vapour deposition (CVD)
- Molecular condensation
- Electrospinning
- Self Assembly

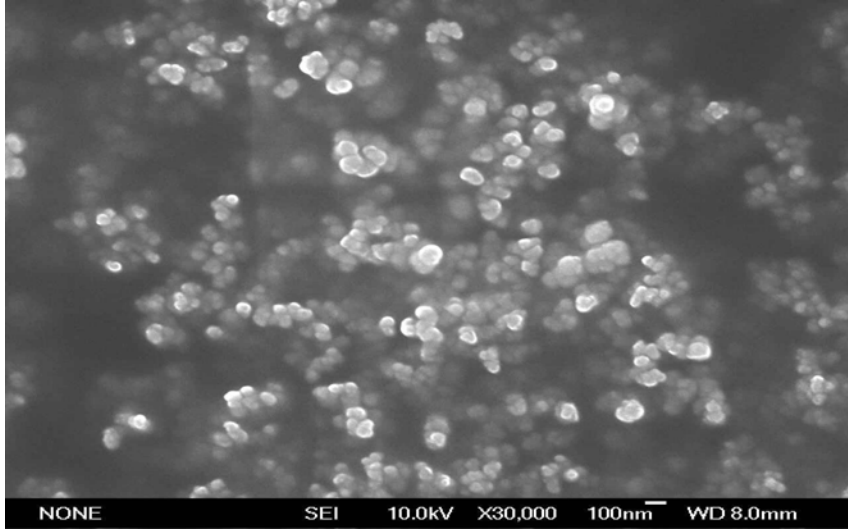
Nano-sized Pb free Alloys manufactured

1. Sn_{3,0}Ag_{0,5}Cu - 219 °C
2. Sn_{4,0}Ag_{0,5}Cu - 217 °C
3. Sn_{0,4}Co_{0,7}Cu - 224 °C
4. Sn₅₇Bi - 139 °C

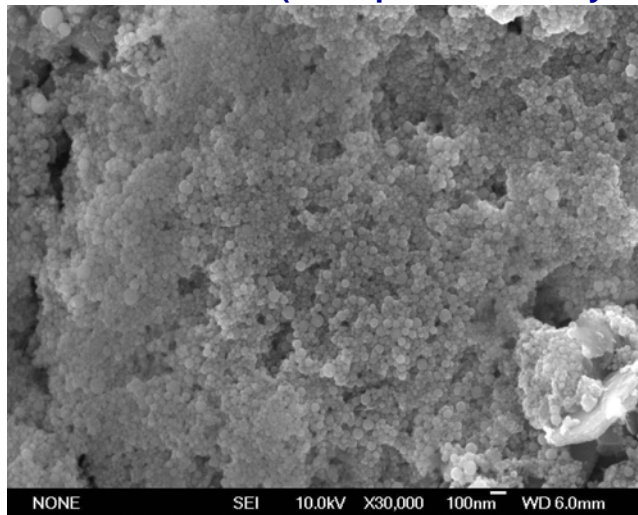
Sn_{3,0}Ag_{0,5}Cu nanoparticles



Sn_{0,4}Co_{0,7}Cu nanoparticles

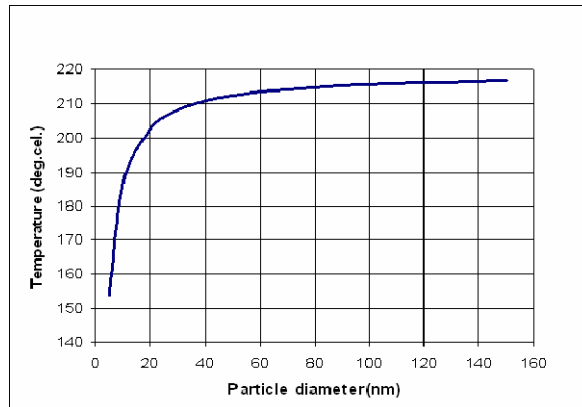


High volume of nanoparticles produced with good size control and distribution (Example: SAC305 system)



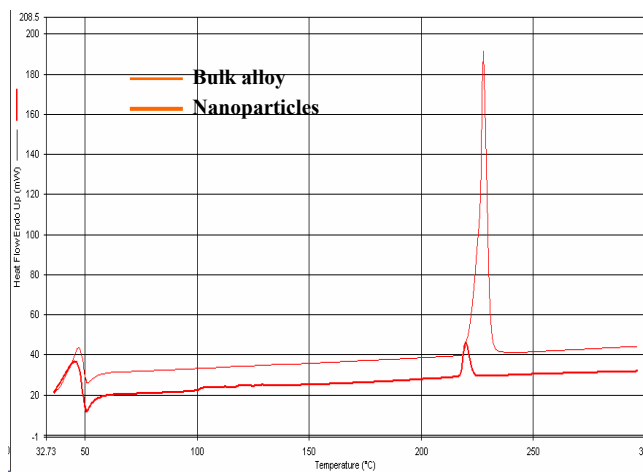
Melting Point Depression

$$\Delta T = T_m^{bulk} - T_m(r) = \frac{2T_m^{bulk}}{H_m^{bulk} \rho_s r} \left[\sigma_s - \sigma_L \left(\frac{\rho_s}{\rho_L} \right)^{\frac{2}{3}} \right]$$



Sn_{4,0}Ag_{0,5}Cu Nano alloy particles

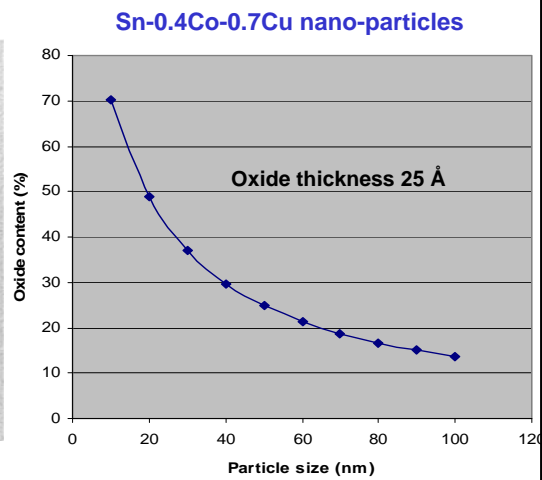
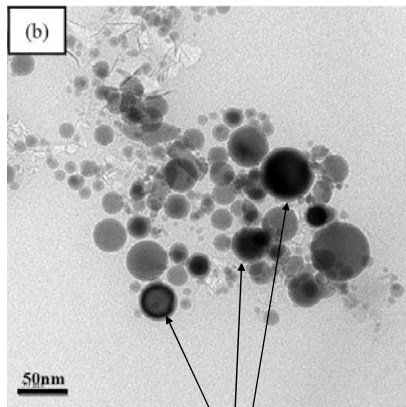
DSC Analysis



Onset calculation showed about 3°C depression in melting point.

Sn_{4,0}Ag_{0,5}Cu

Oxide content in nano-particles



Details of Reflow Oven with N2 Gas



Purity of Nitrogen gas used – 99.996% at 1 second pulse rate.

Solder paste formulation

Composition:

1. Lead free Alloy Nanoparticles - ~ 50 wt%
in paraffin oil
2. Flux - ~ 50 wt%

Component mounting

Components used:

1. 1812 Capacitors with tin metallization on end (big).
2. 1206 Capacitors with tin metallization on end (small).

Test Board:

1. Ceramic test board

Reflow conditions:

1. Reflow temperature - 290°C (for 2 Minutes)
2. Atmosphere - Nitrogen (Inert)

Component Mounting Test

Sn0.4Co0.7Cu Nanoparticles with active



Big Components, 1812



Small Component, 1206

Contact Resistance by four probe - **0.2 mΩ** in all cases.

Sn4.0Ag0.5Cu Nanoparticles with active



Big Component, 1812



Small Components, 1206

Future Research Topics

- **Aim: Develop prototype nanosolder lead free paste in 3-5 years time**
- **Issues:**
 - Single particle melting point measurement techniques
 - Flux formulation and characterisation
 - Paste Characterisation
 - Application Technology including stencil printing, dispensing and jetting
 - Reliability characterisation and testing

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